Application News

Shimadzu Energy Dispersive X-Ray Fluorescence Spectrometer EDX-8000/8100

Quantitative Analysis of Fluorine by EDXRF: Powder and Fluorine-Containing Film

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User Benefits

- Although complicated sample preparation such as dissolution or cutting is necessary when using ion chromatograph or SEM-EDS, EDX allows direct analysis.
- Quantitative analysis of fluorine in samples containing less than 1 % is possible regardless of the sample form including solids, powders, and films.
- Operation of the instrument is simple, and analyses can be carried out immediately, even by inexperienced personnel.

■ Introduction

Fluoride compounds have various properties such as a flame retardancy, water repellence, antifouling property, and heat resistance. They are used in a wide range of fields from daily necessities to semiconductors. The ion chromatograph and SEM-EDS are mainly used for the analyses of fluoride compounds, but complicated sample preparation is necessary for them. On the other hand, the feature of the energy dispersive X-ray fluorescence spectrometer (EDXRF) is that it can perform analysis without chemical pretreatment. Fluorine, which is generally difficult to analyze, can be quantified with EDX-8000/8100, which has high sensitivity for light elements.

This article introduces the following two analysis examples.

- 1. Quantitative analysis of fluorine in powder samples (limit of detection, repeatability)
- 2. Analysis of the coating weight of a fluororesin coating agent (quantitation of coating weight by fundamental parameter (FP) method, limit of detection, repeatability)

1. Quantitative Analysis of Fluorine in Powder Samples

■ Standard Samples

Standard samples with 3 fluorine (F) concentration levels were prepared by adding lithium fluoride (LiF) powder to cellulose powder, thoroughly mixing the material, and forming briquettes (Fig. 1) by compression molding. Table 1 shows the F contents of the standard samples.



Fig. 1 Appearance of Standard Sample Briquette

Table 1 F Contents of Standard Samples

	[ppm
Standard sample	F content
1)	0
2	2500
3	5000

■ Qualitative Profile of F

Fig. 2 shows the overlay of the profiles of the 3 standard samples.

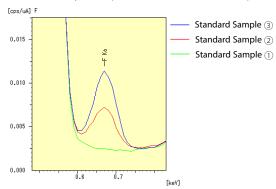


Fig. 2 Overlay of FKα Profiles

■ Calibration Curve

Fig. 3 shows the calibration curve of F prepared using the 3 standard samples (n = 3). Accuracy is 55 [ppm] at an integral time of 300 [s], the theoretical limit of detection is $203 [ppm]^*$, and quantitation is possible at concentrations of 1 % or less.

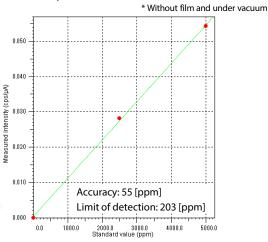


Fig. 3 Calibration Curve of F in Cellulose Powder

■ Repeatability

Table 2 shows the results of a simple repeatability test (n = 10) of the 5000 ppm standard sample \Im .

Table 2 Results of Repeatability Test

5019 [ppm]
125.0 [ppm]
2.5 [%]

2. Analysis of Coating Film Weight of **Fluororesin Coating Agent**

■ Samples

Samples were prepared by spraying a spray-type fluororesin (PTFE; CF₂) coating agent on glass plates, and a quantitative analysis of the coating film weight of the coating agent was conducted. Fig. 4 shows the appearance of 3 samples with different coating weights.

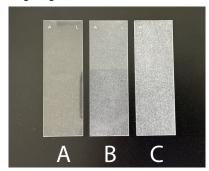


Fig. 4 Appearance of Samples (From Left, Coating Film Weight in Order of A, B, C)

■ Qualitative Profiles of F

Fig. 5 shows the overlay of the profiles of the 3 samples coated with the fluororesin.

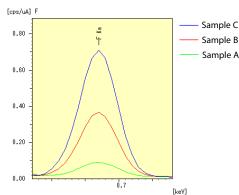


Fig. 5 Overlay of FKα Profiles

■ Quantitative Analysis of Coating Film Weight by FP Method

Table 3 summarizes the results of the quantitative analysis of the coating film weights of the 3 samples. These quantitation results are based on the assumption that the composition of the glass substrate is SiO₂ and all compositions of the fluororesin coating agent are PTFE (CF₂).

Table 3 Results of Quantitative Analysis of Coating Weight of Fluororesin (PTFE)

[µg/cm-]
PTFE coating film weight
10.4
52.6
127.5

■ Limit of Detection

A calibration curve (Fig. 6) including a blank was prepared using the quantitation values shown in Table 3 as a standard value and the limit of detection was calculated. It can be understood that the theoretical limit of detection is $0.13 \, [\mu g/cm^2]$.

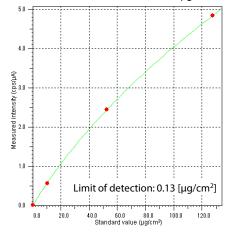


Fig. 6 Calibration Curve

■ Repeatability

Table 4 shows the results of a simple repeatability test (n = 10)of sample C.

Table 4 Results of Repeatability Test

Average value	126.6 [μg/cm²]
Standard deviation	0.47 [μg/cm²]
Coefficient of variation	0.37 [%]

■ Conclusion

It was found that EDXRF is effective for analysis of fluorine. The features are summarized below.

- 1. No chemical pretreatment required Measurement can be performed simply by placing the sample on the instrument without complicated pretreatment.
- 2. Analytical precision

The lower limit of detection of F in powders and solids is about 200 ppm, and quantitative analysis of contents of 1 %

In film thickness analysis, quantitation on the nm to μm order is possible in the case of PTFE, which can be expected to contribute to quality control.

User-friendliness

Operation of the instrument is simple, and even inexperienced people can analyze samples easily.

4. Non-destructive analysis

The sample after the measurement can be used for other analyses.

■ Measurement Conditions

Instrument	: EDX-8000/8100
Element	: ₉ F
Analysis group	: Quantitative analysis
Analysis methods	: 1. Calibration curve method, 2. Film FP method
Detector	: SDD
X-ray tube	: Rh target
Tube voltage - current	: : 15 [kV] – Auto [μΑ]
Collimator	: 10 [mmφ]
Primary filter	: None
Atmosphere	: Vacuum
Integral time	: 300 [s]
Dead time	: Max. 30 [%]

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